

SCANNING ELECTRON MICROSCOPE(SEM)

Make : TESCAN

Model : VEGA3

Magnification: x 30 – x 3,00,000

Specimen size: Max. 150 mm diameter

Accelerating voltage: 0.3 – 30 kV

Resolution : 3.5 nm @ 25kV high vacuum mode

Attachments : Energy-dispersive X-ray. Spectroscopy (EDS) &
Backscattered Electron Detector (BSED)



True Windows NT environment:

- Image management system for image processing, searching and archiving
- Network capability to transfer SEM images and data to external PCs and servers

Applications:

- To study surface morphology of samples
- Evaluation of crystallographic orientation